

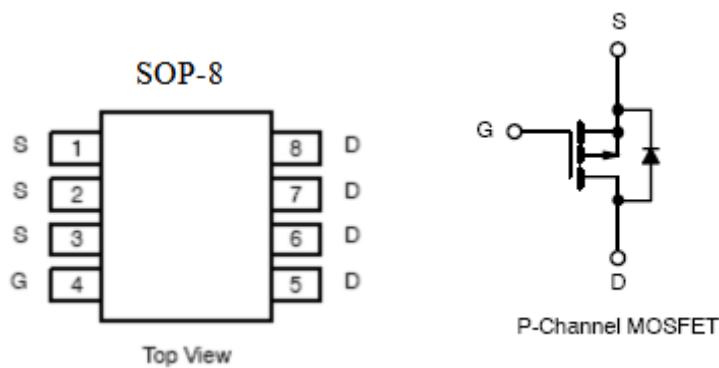
1. Features

- $R_{DS(on)}=18\text{m}\Omega(\text{typ}) @ V_{GS}=-10 \text{ V}$
- Super low gate charge
- Green device available
- Excellent Cdv/dt effect decline
- Advanced high cell density trench technology

2. Description

The KIA7P03A is the high cell density trenched P-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The KIA7P03A meet the RoHs and Green Product requirement.

3. Symbol



4. Absolute maximum ratings

($T_A=25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Rating	Units
Drain-source voltage	V_{DSS}	-30	V
Gate-source voltage	V_{GS}	± 20	V
Continuous drain current V_{GS} @-10V ¹	I_D	-7.5	A
$T_A=25^\circ\text{C}$		-6	
Pulsed drain current ²	I_{DM}	-50	A
Single pulse avalanche energy ³	EAS	72.2	mJ
Avalanche current	I_{AS}	-38	A
Total power dissipation ⁴	P_D	3.1	W
$T_A=70^\circ\text{C}$		2	W
Junction and storage temperature range	T_J, T_{STG}	-55 to 150	°C
Thermal resistance-junction to ambient ¹	$R_{\theta JA}$	75	°C/W
Thermal resistance-junction to ambient ¹ ($t \leq 10\text{s}$)		40	
Thermal resistance-junction to case ¹	$R_{\theta JC}$	24	

5.Electrical characteristics

($T_J=25^\circ\text{C}$,unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-Source breakdown voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
BV_{DSS} Temperature coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Reference to 25°C , $I_{\text{D}}=1\text{mA}$	-	0.022	-	V/ $^\circ\text{C}$
Drain-Source Leakage Current	I_{DSS}	$V_{\text{DS}}=-24\text{V}, V_{\text{GS}}=0\text{V}, T_J=25^\circ\text{C}$	-	-	-1	μA
		$V_{\text{DS}}=-24\text{V}, V_{\text{GS}}=0\text{V}, T_J=55^\circ\text{C}$	-	-	-5	
Gate-source leakage current	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Gate threshold voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	-1	-	-2.5	V
$V_{\text{GS}(\text{th})}$ Temperature coefficient	$\Delta V_{\text{GS}(\text{th})}$		-	4.6	-	mV/ $^\circ\text{C}$
Static drain-source on- resistance ²	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-6\text{A}$	-	18	20	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-4\text{A}$	-	27	32	
Forward transconductance	g_{FS}	$V_{\text{DS}}=-5\text{V}, I_{\text{D}}=-6\text{A}$	-	17	-	S
Gate resistance	R_g	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=0\text{V}, f=1.0\text{MHz}$	-	13	-	Ω
Total gate charge(-4.5V)	Q_g	$V_{\text{DS}}=-15\text{V}, V_{\text{GS}}=-4.5\text{V}$ $I_{\text{D}}=-6\text{A}$	-	12.6	-	nC
Gate-source charge	Q_{gs}		-	4.8	-	
Gate-drain charge	Q_{gd}		-	4.8	-	
Turn-on delay time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=-15\text{V}, R_{\text{G}}=3.3\Omega, V_{\text{GS}}=-10\text{V}$ $I_{\text{D}}=-6\text{A}$	-	4.6	-	ns
Rise time	t_r		-	14.8	-	
Turn-off delay time	$t_{\text{d}(\text{off})}$		-	41	-	
Fall time	t_f		-	19.6	-	
Input capacitance	C_{iss}	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=-15\text{V}$ $f=1.0\text{MHz}$	-	1345	-	pF
Output capacitance	C_{oss}		-	194	-	
Reverse transfer capacitance	C_{rss}		-	158	-	
Diode characteristics						
Continuous source current ^{1.5}	I_s	$V_G=V_D=0\text{V}, \text{Force current}$	-	-	-7.5	A
Pulsed source current ^{2.5}	I_{SM}		-	-	-50	A
Diode forward voltage ²	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{S}}=-1\text{A}, T_J=25^\circ\text{C}$	-	-	-1.2	V
Reverse recovery time	t_{rr}	$I_F=-6\text{A}, dI/dt=100\text{A/us}, T_J=25^\circ\text{C}$	-	16.3	-	nS
Reverse recovery charge	Q_{rr}		-	5.9	-	nC

Note:1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

2. The data tested by pulsed, pulse width $\leqslant 300\text{us}$,duty cycle $\leqslant 2\%$.
3. The EAS data shows Max.rating. The test condition is $V_{\text{DD}}=-25\text{V}, V_{\text{GS}}=-10\text{V}, L=0.1\text{mH}, I_{\text{AS}}=-38\text{A}$.
4. The power dissipation is limited by 150°C junction temperature.
5. The data is theoretically the same as I_{D} and I_{DM} , in real applications, should be limited by total power dissipation.

6. Test circuits and waveforms

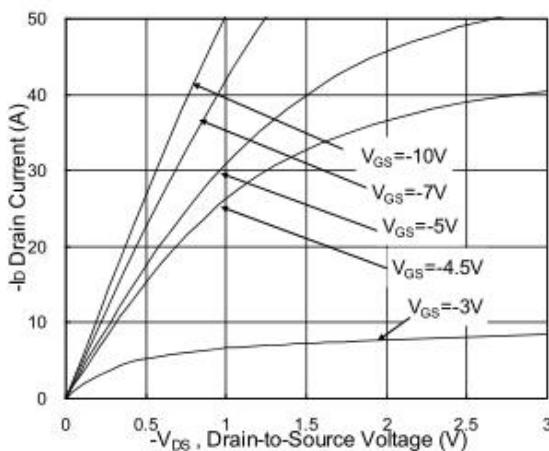


Fig.1 Typical Output Characteristics

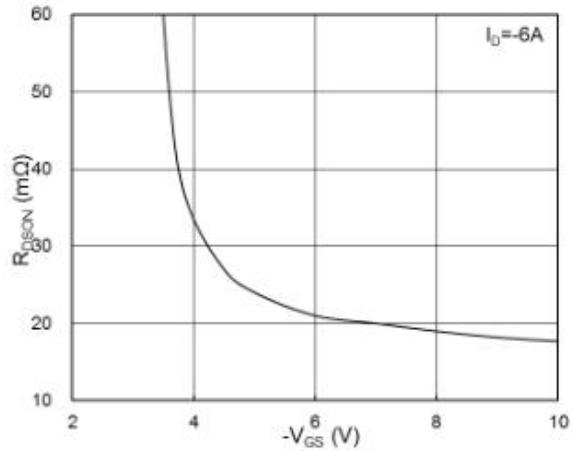


Fig.2 On-Resistance v.s Gate-Source

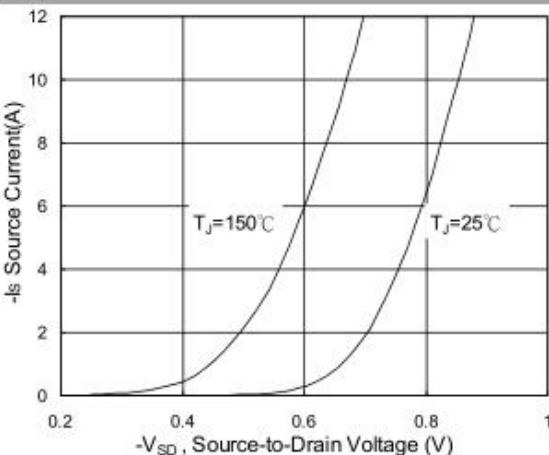


Fig.3 Forward Characteristics of Reverse

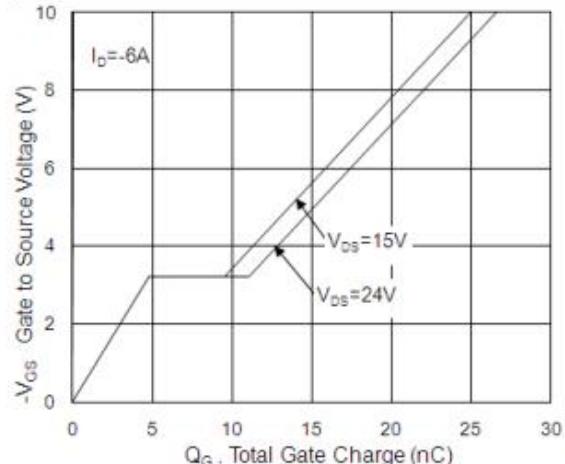


Fig.4 Gate-Charge Characteristics

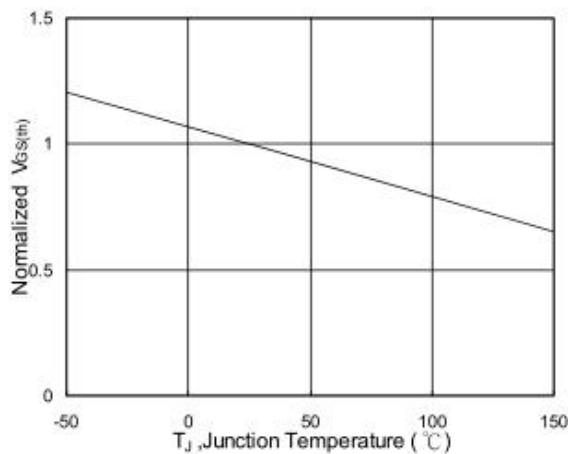


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

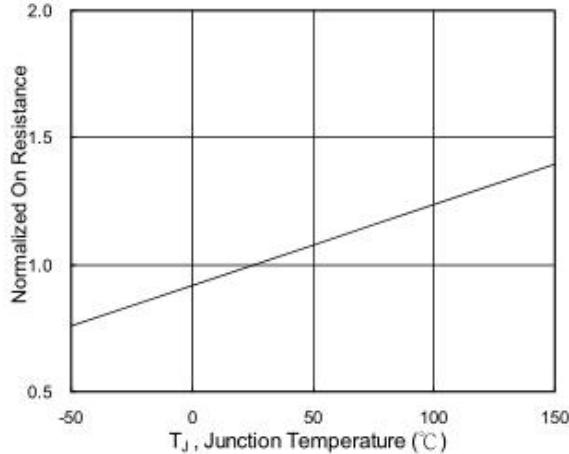


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

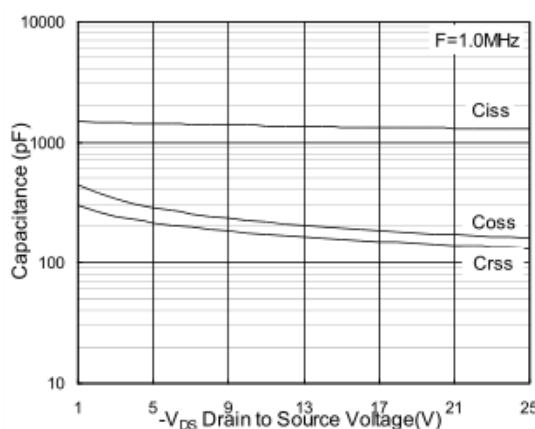


Fig.7 Capacitance

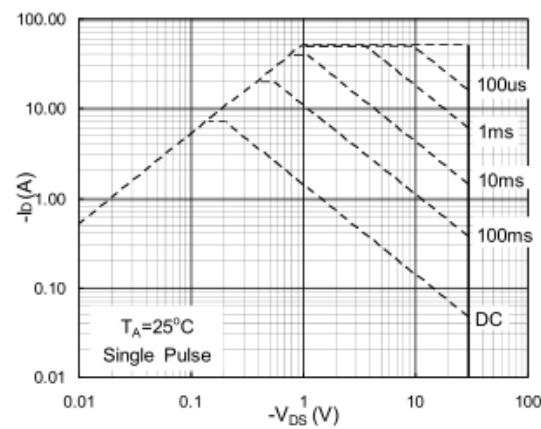


Fig.8 Safe Operating Area

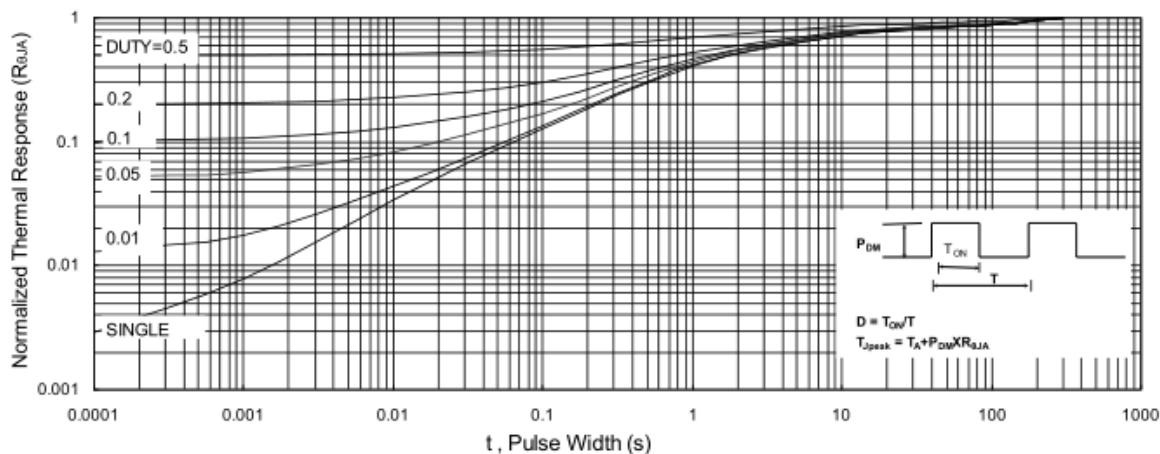


Fig.9 Normalized Maximum Transient Thermal Impedance

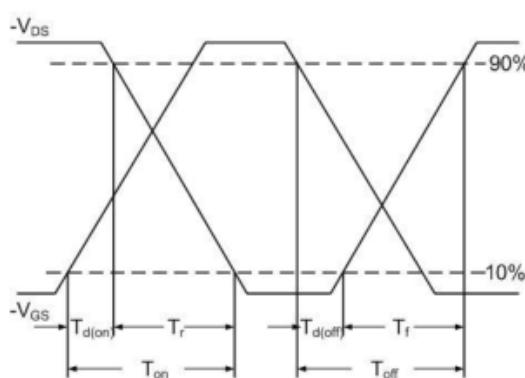


Fig.10 Switching Time Waveform

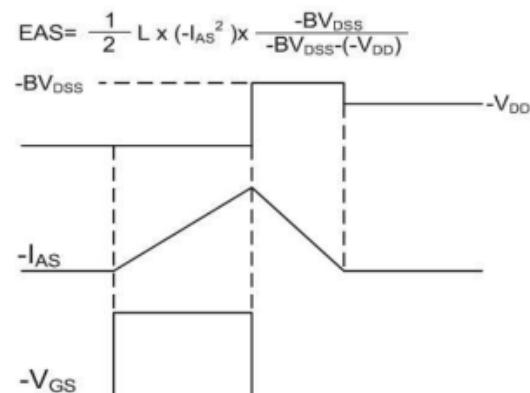


Fig.11 Unclamped Inductive Switching Waveform